DOCUMENT CHANGE REQUEST					
DCR number	582	2 Changes required for: N/A			Originator: Alexander Kovach
Date: 2010/03	/15	5 Date sent: 2010/03/15			Organisation: DLR
Status: IMPLEMENTED					
Title:	Crystal Units in Metal Holder, based on type T807, Frequency range:4.0-140MHz.				
Number:	3501/001 Issue: 3				
Other documents affected:					
3501/002-4, 3501/008-4, 3501/009-4, 3501/011-3, 3501/012-3, 3501/018-3, 3501/019-3					
Page:					
§ 9.5.1 Fine Leak					
Paragraph:					
§ 9.5.1 Fine Leak					
Original wording:					
Proposed wording:					
The crystal units shall be subjected to Test MIL-STD-202G, method 112E, procedure IIIa.					
Justification:					
Fine seal test, set in KVG as a standard, is more related to MIL-STD-202G, method 112E, procedure IIIa, than to IEC 68-2- 17. Therefore we are raising a DCR against generic specification to be put as an appendix, and to be apply only to KVG products. As justification we are refering to QA-1298, page 22 and 23.					
Attachments:					
N/A					
Modifications:					
Appendix B - Agreed Deviations for KVG Quartz Crystal Technology GmbH (D):					
ITEMS AFFECTED Para. 4.2.2 Para. 4.2.3 Para. 4.2.4 Para. 4.2.5 DESCRIPTION OF DEVIATION					
Para. 9.5.1, Seal Test Fine Leak: The crystal units shall be subjected to MIL-STD-202, Method 112, Procedure IIIa					

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Approval signature:

R. C. Mari-9

Date signed:

2010-03-15